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### Understanding [Embedded - FPGAs \(Field Programmable Gate Array\)](#)

Embedded - FPGAs, or Field Programmable Gate Arrays, are advanced integrated circuits that offer unparalleled flexibility and performance for digital systems. Unlike traditional fixed-function logic devices, FPGAs can be programmed and reprogrammed to execute a wide array of logical operations, enabling customized functionality tailored to specific applications. This reprogrammability allows developers to iterate designs quickly and implement complex functions without the need for custom hardware.

### Applications of Embedded - FPGAs

The versatility of Embedded - FPGAs makes them indispensable in numerous fields. In telecommunications.

#### Details

Product Status	Obsolete
Number of LABs/CLBs	220000
Number of Logic Elements/Cells	583000
Total RAM Bits	46080000
Number of I/O	840
Number of Gates	-
Voltage - Supply	0.82V ~ 0.88V
Mounting Type	Surface Mount
Operating Temperature	-40°C ~ 100°C (TJ)
Package / Case	1932-BBGA, FCBGA
Supplier Device Package	1932-FBGA, FC (45x45)
Purchase URL	<a href="https://www.e-xfl.com/product-detail/intel/5sgsed6n3f45i3n">https://www.e-xfl.com/product-detail/intel/5sgsed6n3f45i3n</a>

**Table 7. Recommended Transceiver Power Supply Operating Conditions for Stratix V GX, GS, and GT Devices (Part 2 of 2)**

Symbol	Description	Devices	Minimum <sup>(4)</sup>	Typical	Maximum <sup>(4)</sup>	Unit
$V_{CCR\_GXBR}$ (2)	Receiver analog power supply (right side)	GX, GS, GT	0.82	0.85	0.88	V
			0.87	0.90	0.93	
			0.97	1.0	1.03	
			1.03	1.05	1.07	
$V_{CCR\_GTBR}$	Receiver analog power supply for GT channels (right side)	GT	1.02	1.05	1.08	V
$V_{CCT\_GXBL}$ (2)	Transmitter analog power supply (left side)	GX, GS, GT	0.82	0.85	0.88	V
			0.87	0.90	0.93	
			0.97	1.0	1.03	
			1.03	1.05	1.07	
$V_{CCT\_GXBR}$ (2)	Transmitter analog power supply (right side)	GX, GS, GT	0.82	0.85	0.88	V
			0.87	0.90	0.93	
			0.97	1.0	1.03	
			1.03	1.05	1.07	
$V_{CCT\_GTBR}$	Transmitter analog power supply for GT channels (right side)	GT	1.02	1.05	1.08	V
$V_{CCL\_GTBR}$	Transmitter clock network power supply	GT	1.02	1.05	1.08	V
$V_{CCH\_GXBL}$	Transmitter output buffer power supply (left side)	GX, GS, GT	1.425	1.5	1.575	V
$V_{CCH\_GXBR}$	Transmitter output buffer power supply (right side)	GX, GS, GT	1.425	1.5	1.575	V

**Notes to Table 7:**

- (1) This supply must be connected to 3.0 V if the CMU PLL, receiver CDR, or both, are configured at a base data rate > 6.5 Gbps. Up to 6.5 Gbps, you can connect this supply to either 3.0 V or 2.5 V.
- (2) Refer to Table 8 to select the correct power supply level for your design.
- (3) When using ATX PLLs, the supply must be 3.0 V.
- (4) This value describes the budget for the DC (static) power supply tolerance and does not include the dynamic tolerance requirements. Refer to the PDN tool for the additional budget for the dynamic tolerance requirements.

### I/O Pin Leakage Current

Table 9 lists the Stratix V I/O pin leakage current specifications.

**Table 9. I/O Pin Leakage Current for Stratix V Devices <sup>(1)</sup>**

Symbol	Description	Conditions	Min	Typ	Max	Unit
$I_I$	Input pin	$V_I = 0 \text{ V to } V_{CCIO\text{MAX}}$	-30	—	30	$\mu\text{A}$
$I_{OZ}$	Tri-stated I/O pin	$V_O = 0 \text{ V to } V_{CCIO\text{MAX}}$	-30	—	30	$\mu\text{A}$

**Note to Table 9:**

(1) If  $V_O = V_{CCIO}$  to  $V_{CCIO\text{MAX}}$ , 100  $\mu\text{A}$  of leakage current per I/O is expected.

### Bus Hold Specifications

Table 10 lists the Stratix V device family bus hold specifications.

**Table 10. Bus Hold Parameters for Stratix V Devices**

Parameter	Symbol	Conditions	V <sub>CCIO</sub>										Unit
			1.2 V		1.5 V		1.8 V		2.5 V		3.0 V		
			Min	Max	Min	Max	Min	Max	Min	Max	Min	Max	
Low sustaining current	I <sub>SUSL</sub>	V <sub>IN</sub> > V <sub>IL</sub> (maximum)	22.5	—	25.0	—	30.0	—	50.0	—	70.0	—	μA
High sustaining current	I <sub>SUSH</sub>	V <sub>IN</sub> < V <sub>IH</sub> (minimum)	−22.5	—	−25.0	—	−30.0	—	−50.0	—	−70.0	—	μA
Low overdrive current	I <sub>ODL</sub>	0V < V <sub>IN</sub> < V <sub>CCIO</sub>	—	120	—	160	—	200	—	300	—	500	μA
High overdrive current	I <sub>ODH</sub>	0V < V <sub>IN</sub> < V <sub>CCIO</sub>	—	−120	—	−160	—	−200	—	−300	—	−500	μA
Bus-hold trip point	V <sub>TRIP</sub>	—	0.45	0.95	0.50	1.00	0.68	1.07	0.70	1.70	0.80	2.00	V

### On-Chip Termination (OCT) Specifications

If you enable OCT calibration, calibration is automatically performed at power-up for I/Os connected to the calibration block. Table 11 lists the Stratix V OCT termination calibration accuracy specifications.

**Table 11. OCT Calibration Accuracy Specifications for Stratix V Devices <sup>(1)</sup> (Part 1 of 2)**

Symbol	Description	Conditions	Calibration Accuracy				Unit
			C1	C2,I2	C3,I3, I3YY	C4,I4	
25- $\Omega$ $R_S$	Internal series termination with calibration (25- $\Omega$ setting)	$V_{\text{CCIO}} = 3.0, 2.5, 1.8, 1.5, 1.2 \text{ V}$	$\pm 15$	$\pm 15$	$\pm 15$	$\pm 15$	%

**Table 11. OCT Calibration Accuracy Specifications for Stratix V Devices <sup>(1)</sup> (Part 2 of 2)**

Symbol	Description	Conditions	Calibration Accuracy				Unit
			C1	C2,I2	C3,I3,I3YY	C4,I4	
50-Ω R <sub>S</sub>	Internal series termination with calibration (50-Ω setting)	V <sub>CCIO</sub> = 3.0, 2.5, 1.8, 1.5, 1.2 V	±15	±15	±15	±15	%
34-Ω and 40-Ω R <sub>S</sub>	Internal series termination with calibration (34-Ω and 40-Ω setting)	V <sub>CCIO</sub> = 1.5, 1.35, 1.25, 1.2 V	±15	±15	±15	±15	%
48-Ω, 60-Ω, 80-Ω, and 240-Ω R <sub>S</sub>	Internal series termination with calibration (48-Ω, 60-Ω, 80-Ω, and 240-Ω setting)	V <sub>CCIO</sub> = 1.2 V	±15	±15	±15	±15	%
50-Ω R <sub>T</sub>	Internal parallel termination with calibration (50-Ω setting)	V <sub>CCIO</sub> = 2.5, 1.8, 1.5, 1.2 V	-10 to +40	-10 to +40	-10 to +40	-10 to +40	%
20-Ω, 30-Ω, 40-Ω, 60-Ω, and 120-Ω R <sub>T</sub>	Internal parallel termination with calibration (20-Ω, 30-Ω, 40-Ω, 60-Ω, and 120-Ω setting)	V <sub>CCIO</sub> = 1.5, 1.35, 1.25 V	-10 to +40	-10 to +40	-10 to +40	-10 to +40	%
60-Ω and 120-Ω R <sub>T</sub>	Internal parallel termination with calibration (60-Ω and 120-Ω setting)	V <sub>CCIO</sub> = 1.2	-10 to +40	-10 to +40	-10 to +40	-10 to +40	%
25-Ω R <sub>S_left_shift</sub>	Internal left shift series termination with calibration (25-Ω R <sub>S_left_shift</sub> setting)	V <sub>CCIO</sub> = 3.0, 2.5, 1.8, 1.5, 1.2 V	±15	±15	±15	±15	%

**Note to Table 11:**

(1) OCT calibration accuracy is valid at the time of calibration only.

Table 12 lists the Stratix V OCT without calibration resistance tolerance to PVT changes.

**Table 12. OCT Without Calibration Resistance Tolerance Specifications for Stratix V Devices (Part 1 of 2)**

Symbol	Description	Conditions	Resistance Tolerance				Unit
			C1	C2,I2	C3, I3, I3YY	C4, I4	
25-Ω R, 50-Ω R <sub>S</sub>	Internal series termination without calibration (25-Ω setting)	V <sub>CCIO</sub> = 3.0 and 2.5 V	±30	±30	±40	±40	%
25-Ω R <sub>S</sub>	Internal series termination without calibration (25-Ω setting)	V <sub>CCIO</sub> = 1.8 and 1.5 V	±30	±30	±40	±40	%
25-Ω R <sub>S</sub>	Internal series termination without calibration (25-Ω setting)	V <sub>CCIO</sub> = 1.2 V	±35	±35	±50	±50	%

**Table 12. OCT Without Calibration Resistance Tolerance Specifications for Stratix V Devices (Part 2 of 2)**

Symbol	Description	Conditions	Resistance Tolerance				Unit
			C1	C2, I2	C3, I3, I3YY	C4, I4	
50-Ω R <sub>S</sub>	Internal series termination without calibration (50-Ω setting)	V <sub>CCIO</sub> = 1.8 and 1.5 V	±30	±30	±40	±40	%
50-Ω R <sub>S</sub>	Internal series termination without calibration (50-Ω setting)	V <sub>CCIO</sub> = 1.2 V	±35	±35	±50	±50	%
100-Ω R <sub>D</sub>	Internal differential termination (100-Ω setting)	V <sub>CCPD</sub> = 2.5 V	±25	±25	±25	±25	%

Calibration accuracy for the calibrated series and parallel OCTs are applicable at the moment of calibration. When voltage and temperature conditions change after calibration, the tolerance may change.

OCT calibration is automatically performed at power-up for OCT-enabled I/Os. Table 13 lists the OCT variation with temperature and voltage after power-up calibration. Use Table 13 to determine the OCT variation after power-up calibration and Equation 1 to determine the OCT variation without recalibration.

**Equation 1. OCT Variation Without Recalibration for Stratix V Devices <sup>(1), (2), (3), (4), (5), (6)</sup>**

$$R_{OCT} = R_{SCAL} \left( 1 + \left\langle \frac{dR}{dT} \times \Delta T \right\rangle \pm \left\langle \frac{dR}{dV} \times \Delta V \right\rangle \right)$$

**Notes to Equation 1:**

- (1) The R<sub>OCT</sub> value shows the range of OCT resistance with the variation of temperature and V<sub>CCIO</sub>.
- (2) R<sub>SCAL</sub> is the OCT resistance value at power-up.
- (3) ΔT is the variation of temperature with respect to the temperature at power-up.
- (4) ΔV is the variation of voltage with respect to the V<sub>CCIO</sub> at power-up.
- (5) dR/dT is the percentage change of R<sub>SCAL</sub> with temperature.
- (6) dR/dV is the percentage change of R<sub>SCAL</sub> with voltage.

Table 13 lists the on-chip termination variation after power-up calibration.

**Table 13. OCT Variation after Power-Up Calibration for Stratix V Devices (Part 1 of 2) <sup>(1)</sup>**

Symbol	Description	V <sub>CCIO</sub> (V)	Typical	Unit
dR/dV	OCT variation with voltage without recalibration	3.0	0.0297	% / mV
		2.5	0.0344	
		1.8	0.0499	
		1.5	0.0744	
		1.2	0.1241	

## Internal Weak Pull-Up Resistor

Table 16 lists the weak pull-up resistor values for Stratix V devices.

**Table 16. Internal Weak Pull-Up Resistor for Stratix V Devices <sup>(1), (2)</sup>**

Symbol	Description	V <sub>CCIO</sub> Conditions (V) <sup>(3)</sup>	Value <sup>(4)</sup>	Unit
R <sub>PU</sub>	Value of the I/O pin pull-up resistor before and during configuration, as well as user mode if you enable the programmable pull-up resistor option.	3.0 ±5%	25	kΩ
		2.5 ±5%	25	kΩ
		1.8 ±5%	25	kΩ
		1.5 ±5%	25	kΩ
		1.35 ±5%	25	kΩ
		1.25 ±5%	25	kΩ
		1.2 ±5%	25	kΩ

### Notes to Table 16:

- (1) All I/O pins have an option to enable the weak pull-up resistor except the configuration, test, and JTAG pins.
- (2) The internal weak pull-down feature is only available for the JTAG TCK pin. The typical value for this internal weak pull-down resistor is approximately 25 kΩ.
- (3) The pin pull-up resistance values may be lower if an external source drives the pin higher than V<sub>CCIO</sub>.
- (4) These specifications are valid with a ±10% tolerance to cover changes over PVT.

## I/O Standard Specifications

Table 17 through Table 22 list the input voltage (V<sub>IH</sub> and V<sub>IL</sub>), output voltage (V<sub>OH</sub> and V<sub>OL</sub>), and current drive characteristics (I<sub>OH</sub> and I<sub>OL</sub>) for various I/O standards supported by Stratix V devices. These tables also show the Stratix V device family I/O standard specifications. The V<sub>OL</sub> and V<sub>OH</sub> values are valid at the corresponding I<sub>OH</sub> and I<sub>OL</sub>, respectively.

For an explanation of the terms used in Table 17 through Table 22, refer to “Glossary” on page 65. For tolerance calculations across all SSTL and HSTL I/O standards, refer to Altera knowledge base solution rd07262012\_486.

**Table 17. Single-Ended I/O Standards for Stratix V Devices**

I/O Standard	V <sub>CCIO</sub> (V)			V <sub>IL</sub> (V)		V <sub>IH</sub> (V)		V <sub>OL</sub> (V)	V <sub>OH</sub> (V)	I <sub>OL</sub> (mA)	I <sub>OH</sub> (mA)
	Min	Typ	Max	Min	Max	Min	Max	Max	Min		
LVTTTL	2.85	3	3.15	−0.3	0.8	1.7	3.6	0.4	2.4	2	−2
LVC MOS	2.85	3	3.15	−0.3	0.8	1.7	3.6	0.2	V <sub>CCIO</sub> − 0.2	0.1	−0.1
2.5 V	2.375	2.5	2.625	−0.3	0.7	1.7	3.6	0.4	2	1	−1
1.8 V	1.71	1.8	1.89	−0.3	0.35 * V <sub>CCIO</sub>	0.65 * V <sub>CCIO</sub>	V <sub>CCIO</sub> + 0.3	0.45	V <sub>CCIO</sub> − 0.45	2	−2
1.5 V	1.425	1.5	1.575	−0.3	0.35 * V <sub>CCIO</sub>	0.65 * V <sub>CCIO</sub>	V <sub>CCIO</sub> + 0.3	0.25 * V <sub>CCIO</sub>	0.75 * V <sub>CCIO</sub>	2	−2
1.2 V	1.14	1.2	1.26	−0.3	0.35 * V <sub>CCIO</sub>	0.65 * V <sub>CCIO</sub>	V <sub>CCIO</sub> + 0.3	0.25 * V <sub>CCIO</sub>	0.75 * V <sub>CCIO</sub>	2	−2

**Table 19. Single-Ended SSTL, HSTL, and HSUL I/O Standards Signal Specifications for Stratix V Devices (Part 2 of 2)**

I/O Standard	$V_{IL(DC)}$ (V)		$V_{IH(DC)}$ (V)		$V_{IL(AC)}$ (V)	$V_{IH(AC)}$ (V)	$V_{OL}$ (V)	$V_{OH}$ (V)	$I_{ol}$ (mA)	$I_{oh}$ (mA)
	Min	Max	Min	Max	Max	Min	Max	Min		
HSTL-18 Class I	—	$V_{REF} - 0.1$	$V_{REF} + 0.1$	—	$V_{REF} - 0.2$	$V_{REF} + 0.2$	0.4	$V_{CCIO} - 0.4$	8	-8
HSTL-18 Class II	—	$V_{REF} - 0.1$	$V_{REF} + 0.1$	—	$V_{REF} - 0.2$	$V_{REF} + 0.2$	0.4	$V_{CCIO} - 0.4$	16	-16
HSTL-15 Class I	—	$V_{REF} - 0.1$	$V_{REF} + 0.1$	—	$V_{REF} - 0.2$	$V_{REF} + 0.2$	0.4	$V_{CCIO} - 0.4$	8	-8
HSTL-15 Class II	—	$V_{REF} - 0.1$	$V_{REF} + 0.1$	—	$V_{REF} - 0.2$	$V_{REF} + 0.2$	0.4	$V_{CCIO} - 0.4$	16	-16
HSTL-12 Class I	-0.15	$V_{REF} - 0.08$	$V_{REF} + 0.08$	$V_{CCIO} + 0.15$	$V_{REF} - 0.15$	$V_{REF} + 0.15$	$0.25^* V_{CCIO}$	$0.75^* V_{CCIO}$	8	-8
HSTL-12 Class II	-0.15	$V_{REF} - 0.08$	$V_{REF} + 0.08$	$V_{CCIO} + 0.15$	$V_{REF} - 0.15$	$V_{REF} + 0.15$	$0.25^* V_{CCIO}$	$0.75^* V_{CCIO}$	16	-16
HSUL-12	—	$V_{REF} - 0.13$	$V_{REF} + 0.13$	—	$V_{REF} - 0.22$	$V_{REF} + 0.22$	$0.1^* V_{CCIO}$	$0.9^* V_{CCIO}$	—	—

**Table 20. Differential SSTL I/O Standards for Stratix V Devices**

I/O Standard	$V_{CCIO}$ (V)			$V_{SWING(DC)}$ (V)		$V_{X(AC)}$ (V)			$V_{SWING(AC)}$ (V)	
	Min	Typ	Max	Min	Max	Min	Typ	Max	Min	Max
SSTL-2 Class I, II	2.375	2.5	2.625	0.3	$V_{CCIO} + 0.6$	$V_{CCIO}/2 - 0.2$	—	$V_{CCIO}/2 + 0.2$	0.62	$V_{CCIO} + 0.6$
SSTL-18 Class I, II	1.71	1.8	1.89	0.25	$V_{CCIO} + 0.6$	$V_{CCIO}/2 - 0.175$	—	$V_{CCIO}/2 + 0.175$	0.5	$V_{CCIO} + 0.6$
SSTL-15 Class I, II	1.425	1.5	1.575	0.2	(1)	$V_{CCIO}/2 - 0.15$	—	$V_{CCIO}/2 + 0.15$	0.35	—
SSTL-135 Class I, II	1.283	1.35	1.45	0.2	(1)	$V_{CCIO}/2 - 0.15$	$V_{CCIO}/2$	$V_{CCIO}/2 + 0.15$	$2(V_{IH(AC)} - V_{REF})$	$2(V_{IL(AC)} - V_{REF})$
SSTL-125 Class I, II	1.19	1.25	1.31	0.18	(1)	$V_{CCIO}/2 - 0.15$	$V_{CCIO}/2$	$V_{CCIO}/2 + 0.15$	$2(V_{IH(AC)} - V_{REF})$	—
SSTL-12 Class I, II	1.14	1.2	1.26	0.18	—	$V_{REF} - 0.15$	$V_{CCIO}/2$	$V_{REF} + 0.15$	-0.30	0.30

**Note to Table 20:**

(1) The maximum value for  $V_{SWING(DC)}$  is not defined. However, each single-ended signal needs to be within the respective single-ended limits ( $V_{IH(DC)}$  and  $V_{IL(DC)}$ ).

**Table 21. Differential HSTL and HSUL I/O Standards for Stratix V Devices (Part 1 of 2)**

I/O Standard	$V_{CCIO}$ (V)			$V_{DIF(DC)}$ (V)		$V_{X(AC)}$ (V)			$V_{CM(DC)}$ (V)			$V_{DIF(AC)}$ (V)	
	Min	Typ	Max	Min	Max	Min	Typ	Max	Min	Typ	Max	Min	Max
HSTL-18 Class I, II	1.71	1.8	1.89	0.2	—	0.78	—	1.12	0.78	—	1.12	0.4	—
HSTL-15 Class I, II	1.425	1.5	1.575	0.2	—	0.68	—	0.9	0.68	—	0.9	0.4	—

**Table 23. Transceiver Specifications for Stratix V GX and GS Devices <sup>(1)</sup> (Part 5 of 7)**

Symbol/ Description	Conditions	Transceiver Speed Grade 1			Transceiver Speed Grade 2			Transceiver Speed Grade 3			Unit
		Min	Typ	Max	Min	Typ	Max	Min	Typ	Max	
Programmable DC gain	DC Gain Setting = 0	—	0	—	—	0	—	—	0	—	dB
	DC Gain Setting = 1	—	2	—	—	2	—	—	2	—	dB
	DC Gain Setting = 2	—	4	—	—	4	—	—	4	—	dB
	DC Gain Setting = 3	—	6	—	—	6	—	—	6	—	dB
	DC Gain Setting = 4	—	8	—	—	8	—	—	8	—	dB
<b>Transmitter</b>											
Supported I/O Standards	—	1.4-V and 1.5-V PCML									
Data rate (Standard PCS)	—	600	—	12200	600	—	12200	600	—	8500/ 10312.5 <sup>(24)</sup>	Mbps
Data rate (10G PCS)	—	600	—	14100	600	—	12500	600	—	8500/ 10312.5 <sup>(24)</sup>	Mbps
Differential on- chip termination resistors	85- $\Omega$ setting	—	85 $\pm$ 20%	—	—	85 $\pm$ 20%	—	—	85 $\pm$ 20%	—	$\Omega$
	100- $\Omega$ setting	—	100 $\pm$ 20%	—	—	100 $\pm$ 20%	—	—	100 $\pm$ 20%	—	$\Omega$
	120- $\Omega$ setting	—	120 $\pm$ 20%	—	—	120 $\pm$ 20%	—	—	120 $\pm$ 20%	—	$\Omega$
	150- $\Omega$ setting	—	150 $\pm$ 20%	—	—	150 $\pm$ 20%	—	—	150 $\pm$ 20%	—	$\Omega$
V <sub>OCM</sub> (AC coupled)	0.65-V setting	—	650	—	—	650	—	—	650	—	mV
V <sub>OCM</sub> (DC coupled)	—	—	650	—	—	650	—	—	650	—	mV
Rise time <sup>(7)</sup>	20% to 80%	30	—	160	30	—	160	30	—	160	ps
Fall time <sup>(7)</sup>	80% to 20%	30	—	160	30	—	160	30	—	160	ps
Intra-differential pair skew	Tx V <sub>CM</sub> = 0.5 V and slew rate of 15 ps	—	—	15	—	—	15	—	—	15	ps
Intra-transceiver block transmitter channel-to- channel skew	x6 PMA bonded mode	—	—	120	—	—	120	—	—	120	ps

**Table 28. Transceiver Specifications for Stratix V GT Devices (Part 1 of 5) <sup>(1)</sup>**

Symbol/ Description	Conditions	Transceiver Speed Grade 2			Transceiver Speed Grade 3			Unit
		Min	Typ	Max	Min	Typ	Max	
Reference Clock								
Supported I/O Standards	Dedicated reference clock pin	1.2-V PCML, 1.4-V PCML, 1.5-V PCML, 2.5-V PCML, Differential LVPECL, LVDS, and HCSL						
	RX reference clock pin	1.4-V PCML, 1.5-V PCML, 2.5-V PCML, LVPECL, and LVDS						
Input Reference Clock Frequency (CMU PLL) <sup>(6)</sup>	—	40	—	710	40	—	710	MHz
Input Reference Clock Frequency (ATX PLL) <sup>(6)</sup>	—	100	—	710	100	—	710	MHz
Rise time	20% to 80%	—	—	400	—	—	400	ps
Fall time	80% to 20%	—	—	400	—	—	400	
Duty cycle	—	45	—	55	45	—	55	%
Spread-spectrum modulating clock frequency	PCI Express (PCIe)	30	—	33	30	—	33	kHz
Spread-spectrum downspread	PCIe	—	0 to −0.5	—	—	0 to −0.5	—	%
On-chip termination resistors <sup>(19)</sup>	—	—	100	—	—	100	—	Ω
Absolute V <sub>MAX</sub> <sup>(3)</sup>	Dedicated reference clock pin	—	—	1.6	—	—	1.6	V
	RX reference clock pin	—	—	1.2	—	—	1.2	
Absolute V <sub>MIN</sub>	—	-0.4	—	—	-0.4	—	—	V
Peak-to-peak differential input voltage	—	200	—	1600	200	—	1600	mV
V <sub>ICM</sub> (AC coupled)	Dedicated reference clock pin	1050/1000 <sup>(2)</sup>			1050/1000 <sup>(2)</sup>			mV
	RX reference clock pin	1.0/0.9/0.85 <sup>(22)</sup>			1.0/0.9/0.85 <sup>(22)</sup>			V
V <sub>ICM</sub> (DC coupled)	HCSL I/O standard for PCIe reference clock	250	—	550	250	—	550	mV

**Table 28. Transceiver Specifications for Stratix V GT Devices (Part 4 of 5) <sup>(1)</sup>**

Symbol/ Description	Conditions	Transceiver Speed Grade 2			Transceiver Speed Grade 3			Unit
		Min	Typ	Max	Min	Typ	Max	
Data rate	GT channels	19,600	—	28,050	19,600	—	25,780	Mbps
Differential on-chip termination resistors	GT channels	—	100	—	—	100	—	Ω
	GX channels	(8)						
V <sub>OCM</sub> (AC coupled)	GT channels	—	500	—	—	500	—	mV
	GX channels	(8)						
Rise/Fall time	GT channels	—	15	—	—	15	—	ps
	GX channels	(8)						
Intra-differential pair skew	GX channels	(8)						
Intra-transceiver block transmitter channel-to- channel skew	GX channels	(8)						
Inter-transceiver block transmitter channel-to- channel skew	GX channels	(8)						
CMU PLL								
Supported Data Range	—	600	—	12500	600	—	8500	Mbps
t <sub>pll_powerdown</sub> <sup>(13)</sup>	—	1	—	—	1	—	—	μs
t <sub>pll_lock</sub> <sup>(14)</sup>	—	—	—	10	—	—	10	μs
ATX PLL								
Supported Data Rate Range for GX Channels	VCO post- divider L=2	8000	—	12500	8000	—	8500	Mbps
	L=4	4000	—	6600	4000	—	6600	Mbps
	L=8	2000	—	3300	2000	—	3300	Mbps
	L=8, Local/Central Clock Divider =2	1000	—	1762.5	1000	—	1762.5	Mbps
Supported Data Rate Range for GT Channels	VCO post- divider L=2	9800	—	14025	9800	—	12890	Mbps
t <sub>pll_powerdown</sub> <sup>(13)</sup>	—	1	—	—	1	—	—	μs
t <sub>pll_lock</sub> <sup>(14)</sup>	—	—	—	10	—	—	10	μs
fPLL								
Supported Data Range	—	600	—	3250/ 3.125 <sup>(23)</sup>	600	—	3250/ 3.125 <sup>(23)</sup>	Mbps
t <sub>pll_powerdown</sub> <sup>(13)</sup>	—	1	—	—	1	—	—	μs

- XFI
- ASI
- HiGig/HiGig+
- HiGig2/HiGig2+
- Serial Data Converter (SDC)
- GPON
- SDI
- SONET
- Fibre Channel (FC)
- PCIe
- QPI
- SFF-8431

Download the Stratix V Characterization Report Tool to view the characterization report summary for these protocols.

## Core Performance Specifications

This section describes the clock tree, phase-locked loop (PLL), digital signal processing (DSP), memory blocks, configuration, and JTAG specifications.

### Clock Tree Specifications

Table 30 lists the clock tree specifications for Stratix V devices.

**Table 30. Clock Tree Performance for Stratix V Devices <sup>(1)</sup>**

Symbol	Performance			Unit
	C1, C2, C2L, I2, and I2L	C3, I3, I3L, and I3YY	C4, I4	
Global and Regional Clock	717	650	580	MHz
Periphery Clock	550	500	500	MHz

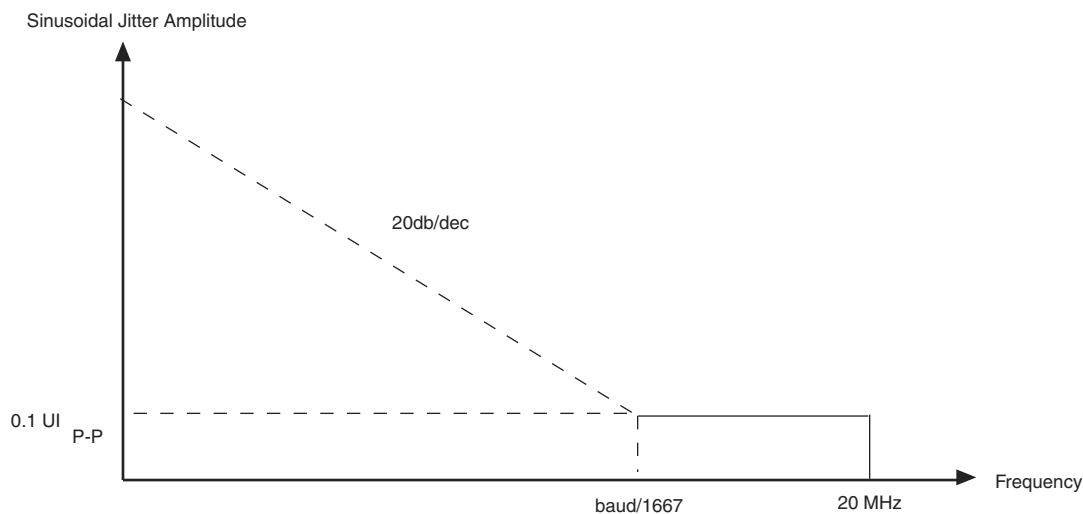
**Note to Table 30:**

(1) The Stratix V ES devices are limited to 600 MHz core clock tree performance.

**Table 38. LVDS Soft-CDR/DPA Sinusoidal Jitter Mask Values for a Data Rate  $\geq 1.25$  Gbps**

Jitter Frequency (Hz)		Sinusoidal Jitter (UI)
F1	10,000	25.000
F2	17,565	25.000
F3	1,493,000	0.350
F4	50,000,000	0.350

Figure 9 shows the LVDS soft-CDR/DPA sinusoidal jitter tolerance specification for a data rate  $< 1.25$  Gbps.

**Figure 9. LVDS Soft-CDR/DPA Sinusoidal Jitter Tolerance Specification for a Data Rate  $< 1.25$  Gbps**

### DLL Range, DQS Logic Block, and Memory Output Clock Jitter Specifications

Table 39 lists the DLL range specification for Stratix V devices. The DLL is always in 8-tap mode in Stratix V devices.

**Table 39. DLL Range Specifications for Stratix V Devices <sup>(1)</sup>**

C1	C2, C2L, I2, I2L	C3, I3, I3L, I3YY	C4,I4	Unit
300-933	300-933	300-890	300-890	MHz

**Note to Table 39:**

- (1) Stratix V devices support memory interface frequencies lower than 300 MHz, although the reference clock that feeds the DLL must be at least 300 MHz. To support interfaces below 300 MHz, multiply the reference clock feeding the DLL to ensure the frequency is within the supported range of the DLL.

Table 40 lists the DQS phase offset delay per stage for Stratix V devices.

**Table 40. DQS Phase Offset Delay Per Setting for Stratix V Devices <sup>(1), (2)</sup> (Part 1 of 2)**

Speed Grade	Min	Max	Unit
C1	8	14	ps
C2, C2L, I2, I2L	8	14	ps
C3,I3, I3L, I3YY	8	15	ps

**Table 40. DQS Phase Offset Delay Per Setting for Stratix V Devices <sup>(1), (2)</sup> (Part 2 of 2)**

Speed Grade	Min	Max	Unit
C4,I4	8	16	ps

**Notes to Table 40:**

- (1) The typical value equals the average of the minimum and maximum values.
- (2) The delay settings are linear with a cumulative delay variation of 40 ps for all speed grades. For example, when using a –2 speed grade and applying a 10-phase offset setting to a 90° phase shift at 400 MHz, the expected average cumulative delay is  $[625 \text{ ps} + (10 \times 10 \text{ ps}) \pm 20 \text{ ps}] = 725 \text{ ps} \pm 20 \text{ ps}$ .

Table 41 lists the DQS phase shift error for Stratix V devices.

**Table 41. DQS Phase Shift Error Specification for DLL-Delayed Clock ( $t_{\text{DQS\_PSERR}}$ ) for Stratix V Devices <sup>(1)</sup>**

Number of DQS Delay Buffers	C1	C2, C2L, I2, I2L	C3, I3, I3L, I3YY	C4,I4	Unit
1	28	28	30	32	ps
2	56	56	60	64	ps
3	84	84	90	96	ps
4	112	112	120	128	ps

**Notes to Table 41:**

- (1) This error specification is the absolute maximum and minimum error. For example, skew on three DQS delay buffers in a –2 speed grade is  $\pm 78 \text{ ps}$  or  $\pm 39 \text{ ps}$ .

Table 42 lists the memory output clock jitter specifications for Stratix V devices.

**Table 42. Memory Output Clock Jitter Specification for Stratix V Devices <sup>(1), (Part 1 of 2)</sup> <sup>(2), (3)</sup>**

Clock Network	Parameter	Symbol	C1		C2, C2L, I2, I2L		C3, I3, I3L, I3YY		C4,I4		Unit
			Min	Max	Min	Max	Min	Max	Min	Max	
Regional	Clock period jitter	$t_{\text{JIT(per)}}$	–50	50	–50	50	–55	55	–55	55	ps
	Cycle-to-cycle period jitter	$t_{\text{JIT(cc)}}$	–100	100	–100	100	–110	110	–110	110	ps
	Duty cycle jitter	$t_{\text{JIT(duty)}}$	–50	50	–50	50	–82.5	82.5	–82.5	82.5	ps
Global	Clock period jitter	$t_{\text{JIT(per)}}$	–75	75	–75	75	–82.5	82.5	–82.5	82.5	ps
	Cycle-to-cycle period jitter	$t_{\text{JIT(cc)}}$	–150	150	–150	150	–165	165	–165	165	ps
	Duty cycle jitter	$t_{\text{JIT(duty)}}$	–75	75	–75	75	–90	90	–90	90	ps

**Table 42. Memory Output Clock Jitter Specification for Stratix V Devices <sup>(1)</sup>, (Part 2 of 2) <sup>(2)</sup>, <sup>(3)</sup>**

Clock Network	Parameter	Symbol	C1		C2, C2L, I2, I2L		C3, I3, I3L, I3YY		C4,I4		Unit
			Min	Max	Min	Max	Min	Max	Min	Max	
PHY Clock	Clock period jitter	$t_{JIT(per)}$	-25	25	-25	25	-30	30	-35	35	ps
	Cycle-to-cycle period jitter	$t_{JIT(cc)}$	-50	50	-50	50	-60	60	-70	70	ps
	Duty cycle jitter	$t_{JIT(duty)}$	-37.5	37.5	-37.5	37.5	-45	45	-56	56	ps

**Notes to Table 42:**

- (1) The clock jitter specification applies to the memory output clock pins generated using differential signal-splitter and DDIO circuits clocked by a PLL output routed on a PHY, regional, or global clock network as specified. Altera recommends using PHY clock networks whenever possible.
- (2) The clock jitter specification applies to the memory output clock pins clocked by an integer PLL.
- (3) The memory output clock jitter is applicable when an input jitter of 30 ps peak-to-peak is applied with bit error rate (BER) -12, equivalent to 14 sigma.

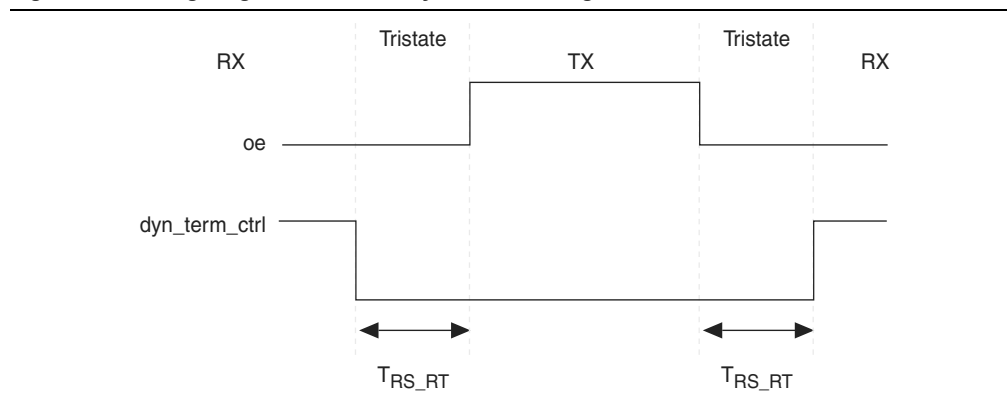
**OCT Calibration Block Specifications**

Table 43 lists the OCT calibration block specifications for Stratix V devices.

**Table 43. OCT Calibration Block Specifications for Stratix V Devices**

Symbol	Description	Min	Typ	Max	Unit
OCTUSRCLK	Clock required by the OCT calibration blocks	—	—	20	MHz
$T_{OCTCAL}$	Number of OCTUSRCLK clock cycles required for OCT $R_S/R_T$ calibration	—	1000	—	Cycles
$T_{OCTSHIFT}$	Number of OCTUSRCLK clock cycles required for the OCT code to shift out	—	32	—	Cycles
$T_{RS\_RT}$	Time required between the <code>dyn_term_ctrl</code> and <code>oe</code> signal transitions in a bidirectional I/O buffer to dynamically switch between OCT $R_S$ and $R_T$ (Figure 10)	—	2.5	—	ns

Figure 10 shows the timing diagram for the `oe` and `dyn_term_ctrl` signals.

**Figure 10. Timing Diagram for `oe` and `dyn_term_ctrl` Signals**

**Table 47. Uncompressed .rbf Sizes for Stratix V Devices**

Family	Device	Package	Configuration .rbf Size (bits)	IOCSR .rbf Size (bits) <sup>(4), (5)</sup>
Stratix V E <sup>(1)</sup>	5SEE9	—	342,742,976	700,888
	5SEEB	—	342,742,976	700,888

**Notes to Table 47:**

- (1) Stratix V E devices do not have PCI Express® (PCIe®) hard IP. Stratix V E devices do not support the CvP configuration scheme.
- (2) 36-transceiver devices.
- (3) 24-transceiver devices.
- (4) File size for the periphery image.
- (5) The IOCSR .rbf size is specifically for the CvP feature.

Use the data in Table 47 to estimate the file size before design compilation. Different configuration file formats, such as a hexadecimal (.hex) or tabular text file (.tff) format, have different file sizes. For the different types of configuration file and file sizes, refer to the Quartus II software. However, for a specific version of the Quartus II software, any design targeted for the same device has the same uncompressed configuration file size. If you are using compression, the file size can vary after each compilation because the compression ratio depends on your design.

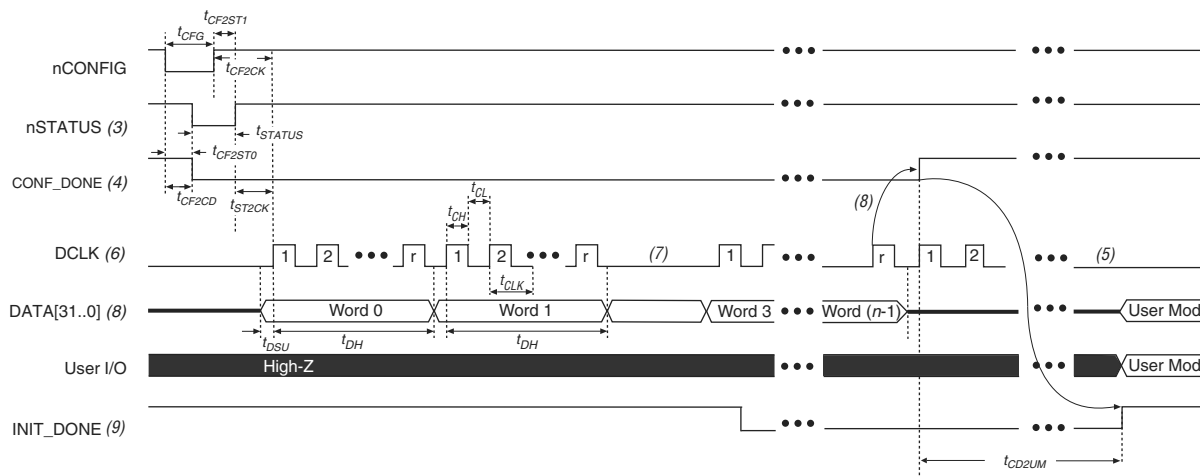


For more information about setting device configuration options, refer to *Configuration, Design Security, and Remote System Upgrades in Stratix V Devices*. For creating configuration files, refer to the *Quartus II Help*.

Table 48 lists the minimum configuration time estimates for Stratix V devices.

**Table 48. Minimum Configuration Time Estimation for Stratix V Devices**

Variant	Member Code	Active Serial <sup>(1)</sup>			Fast Passive Parallel <sup>(2)</sup>		
		Width	DCLK (MHz)	Min Config Time (s)	Width	DCLK (MHz)	Min Config Time (s)
GX	A3	4	100	0.534	32	100	0.067
		4	100	0.344	32	100	0.043
	A4	4	100	0.534	32	100	0.067
	A5	4	100	0.675	32	100	0.084
	A7	4	100	0.675	32	100	0.084
	A9	4	100	0.857	32	100	0.107
	AB	4	100	0.857	32	100	0.107
	B5	4	100	0.676	32	100	0.085
	B6	4	100	0.676	32	100	0.085
	B9	4	100	0.857	32	100	0.107
	BB	4	100	0.857	32	100	0.107
GT	C5	4	100	0.675	32	100	0.084
	C7	4	100	0.675	32	100	0.084

**Figure 13. FPP Configuration Timing Waveform When the DCLK-to-DATA[] Ratio is >1 (1), (2)****Notes to Figure 13:**

- (1) Use this timing waveform and parameters when the DCLK-to-DATA [] ratio is >1. To find out the DCLK-to-DATA [] ratio for your system, refer to Table 49 on page 55.
- (2) The beginning of this waveform shows the device in user mode. In user mode, nCONFIG, nSTATUS, and CONF\_DONE are at logic high levels. When nCONFIG is pulled low, a reconfiguration cycle begins.
- (3) After power-up, the Stratix V device holds nSTATUS low for the time as specified by the POR delay.
- (4) After power-up, before and during configuration, CONF\_DONE is low.
- (5) Do not leave DCLK floating after configuration. You can drive it high or low, whichever is more convenient.
- (6) "r" denotes the DCLK-to-DATA [] ratio. For the DCLK-to-DATA [] ratio based on the decompression and the design security feature enable settings, refer to Table 49 on page 55.
- (7) If needed, pause DCLK by holding it low. When DCLK restarts, the external host must provide data on the DATA [31 . . 0] pins prior to sending the first DCLK rising edge.
- (8) To ensure a successful configuration, send the entire configuration data to the Stratix V device. CONF\_DONE is released high after the Stratix V device receives all the configuration data successfully. After CONF\_DONE goes high, send two additional falling edges on DCLK to begin initialization and enter user mode.
- (9) After the option bit to enable the INIT\_DONE pin is configured into the device, the INIT\_DONE goes low.

## Active Serial Configuration Timing

Table 52 lists the DCLK frequency specification in the AS configuration scheme.

**Table 52. DCLK Frequency Specification in the AS Configuration Scheme <sup>(1), (2)</sup>**

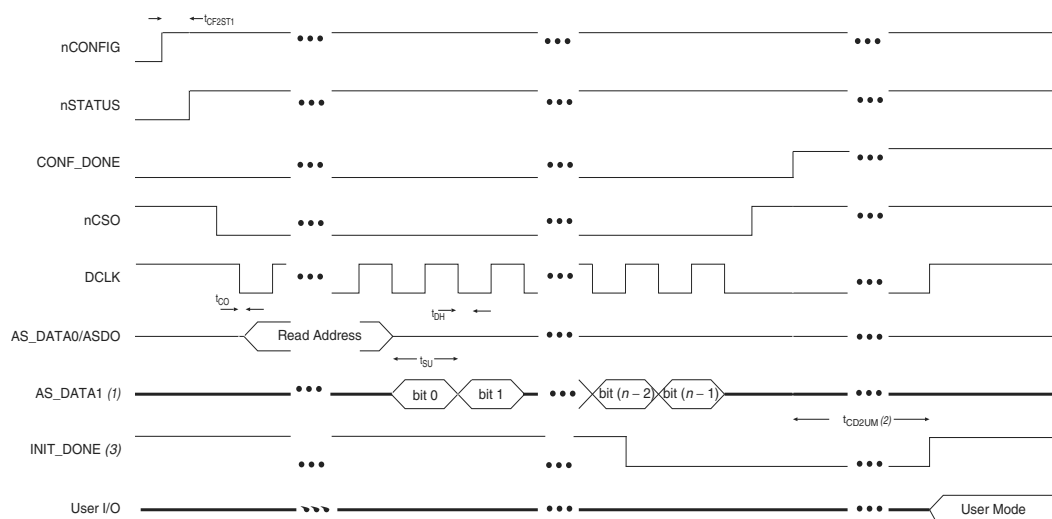
Minimum	Typical	Maximum	Unit
5.3	7.9	12.5	MHz
10.6	15.7	25.0	MHz
21.3	31.4	50.0	MHz
42.6	62.9	100.0	MHz

**Notes to Table 52:**

- (1) This applies to the DCLK frequency specification when using the internal oscillator as the configuration clock source.
- (2) The AS multi-device configuration scheme does not support DCLK frequency of 100 MHz.

Figure 14 shows the single-device configuration setup for an AS ×1 mode.

**Figure 14. AS Configuration Timing**



**Notes to Figure 14:**

- (1) If you are using AS ×4 mode, this signal represents the AS\_DATA [3 : 0] and EPCQ sends in 4-bits of data for each DCLK cycle.
- (2) The initialization clock can be from internal oscillator or CLKUSR pin.
- (3) After the option bit to enable the INIT\_DONE pin is configured into the device, the INIT\_DONE goes low.

Table 53 lists the timing parameters for AS ×1 and AS ×4 configurations in Stratix V devices.

**Table 53. AS Timing Parameters for AS ×1 and AS ×4 Configurations in Stratix V Devices <sup>(1), (2)</sup> (Part 1 of 2)**

Symbol	Parameter	Minimum	Maximum	Units
$t_{CO}$	DCLK falling edge to AS_DATA0/ASDO output	—	2	ns
$t_{SU}$	Data setup time before falling edge on DCLK	1.5	—	ns
$t_H$	Data hold time after falling edge on DCLK	0	—	ns

## Remote System Upgrades

Table 56 lists the timing parameter specifications for the remote system upgrade circuitry.

**Table 56. Remote System Upgrade Circuitry Timing Specifications**

Parameter	Minimum	Maximum	Unit
$t_{RU\_nCONFIG}^{(1)}$	250	—	ns
$t_{RU\_nRSTIMER}^{(2)}$	250	—	ns

**Notes to Table 56:**

- (1) This is equivalent to strobing the reconfiguration input of the ALTREMOTE\_UPDATE megafunction high for the minimum timing specification. For more information, refer to the Remote System Upgrade State Machine section of the “Configuration, Design Security, and Remote System Upgrades in Stratix V Devices” chapter.
- (2) This is equivalent to strobing the reset\_timer input of the ALTREMOTE\_UPDATE megafunction high for the minimum timing specification. For more information, refer to the User Watchdog Timer section of the “Configuration, Design Security, and Remote System Upgrades in Stratix V Devices” chapter.

## User Watchdog Internal Circuitry Timing Specification

Table 57 lists the operating range of the 12.5-MHz internal oscillator.

**Table 57. 12.5-MHz Internal Oscillator Specifications**

Minimum	Typical	Maximum	Units
5.3	7.9	12.5	MHz

## I/O Timing

Altera offers two ways to determine I/O timing—the Excel-based I/O Timing and the Quartus II Timing Analyzer.

Excel-based I/O timing provides pin timing performance for each device density and speed grade. The data is typically used prior to designing the FPGA to get an estimate of the timing budget as part of the link timing analysis. The Quartus II Timing Analyzer provides a more accurate and precise I/O timing data based on the specifics of the design after you complete place-and-route.



You can download the Excel-based I/O Timing spreadsheet from the Stratix V Devices Documentation web page.

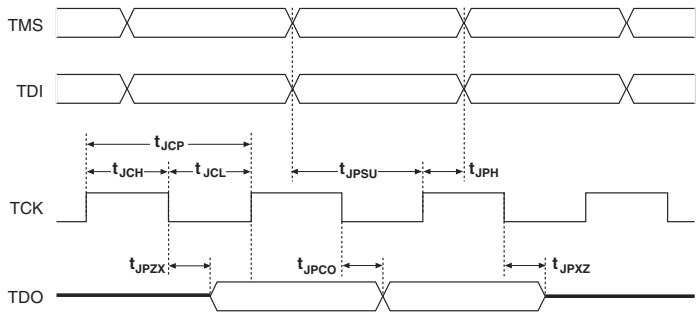
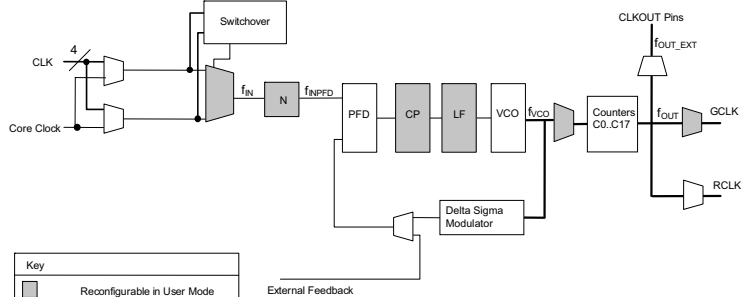
## Programmable IOE Delay

Table 58 lists the Stratix V IOE programmable delay settings.

**Table 58. IOE Programmable Delay for Stratix V Devices (Part 1 of 2)**

Parameter (1)	Available Settings	Min Offset (2)	Fast Model		Slow Model							Unit
			Industrial	Commercial	C1	C2	C3	C4	I2	I3, I3YY	I4	
D1	64	0	0.464	0.493	0.838	0.838	0.924	1.011	0.844	0.921	1.006	ns
D2	32	0	0.230	0.244	0.415	0.415	0.459	0.503	0.417	0.456	0.500	ns

Table 60. Glossary (Part 2 of 4)

Letter	Subject	Definitions
G H I	—	—
J	JTAG Timing Specifications	<p>High-speed I/O block—Deserialization factor (width of parallel data bus).</p> <p>JTAG Timing Specifications:</p> 
K L M N O	—	—
P	PLL Specifications	<p><b>Diagram of PLL Specifications <sup>(1)</sup></b></p>  <p><b>Note:</b>  <sup>(1)</sup> Core Clock can only be fed by dedicated clock input pins or PLL outputs.</p>
Q	—	—
R	R <sub>L</sub>	Receiver differential input discrete resistor (external to the Stratix V device).

**Table 60. Glossary (Part 4 of 4)**

Letter	Subject	Definitions
<b>V</b>	$V_{CM(DC)}$	DC common mode input voltage.
	$V_{ICM}$	Input common mode voltage—The common mode of the differential signal at the receiver.
	$V_{ID}$	Input differential voltage swing—The difference in voltage between the positive and complementary conductors of a differential transmission at the receiver.
	$V_{DIF(AC)}$	AC differential input voltage—Minimum AC input differential voltage required for switching.
	$V_{DIF(DC)}$	DC differential input voltage— Minimum DC input differential voltage required for switching.
	$V_{IH}$	Voltage input high—The minimum positive voltage applied to the input which is accepted by the device as a logic high.
	$V_{IH(AC)}$	High-level AC input voltage
	$V_{IH(DC)}$	High-level DC input voltage
	$V_{IL}$	Voltage input low—The maximum positive voltage applied to the input which is accepted by the device as a logic low.
	$V_{IL(AC)}$	Low-level AC input voltage
	$V_{IL(DC)}$	Low-level DC input voltage
	$V_{OCM}$	Output common mode voltage—The common mode of the differential signal at the transmitter.
	$V_{OD}$	Output differential voltage swing—The difference in voltage between the positive and complementary conductors of a differential transmission at the transmitter.
	$V_{SWING}$	Differential input voltage
	$V_X$	Input differential cross point voltage
	$V_{OX}$	Output differential cross point voltage
<b>W</b>	W	High-speed I/O block—clock boost factor
<b>X</b>	—	—
<b>Y</b>		
<b>Z</b>		

**Table 61. Document Revision History (Part 3 of 3)**

Date	Version	Changes
May 2013	2.7	<ul style="list-style-type: none"> <li>■ Updated Table 2, Table 6, Table 7, Table 20, Table 23, Table 27, Table 47, Table 60</li> <li>■ Added Table 24, Table 48</li> <li>■ Updated Figure 9, Figure 10, Figure 11, Figure 12</li> </ul>
February 2013	2.6	<ul style="list-style-type: none"> <li>■ Updated Table 7, Table 9, Table 20, Table 23, Table 27, Table 30, Table 31, Table 35, Table 46</li> <li>■ Updated “Maximum Allowed Overshoot and Undershoot Voltage”</li> </ul>
December 2012	2.5	<ul style="list-style-type: none"> <li>■ Updated Table 3, Table 6, Table 7, Table 8, Table 23, Table 24, Table 25, Table 27, Table 30, Table 32, Table 35</li> <li>■ Added Table 33</li> <li>■ Added “Fast Passive Parallel Configuration Timing”</li> <li>■ Added “Active Serial Configuration Timing”</li> <li>■ Added “Passive Serial Configuration Timing”</li> <li>■ Added “Remote System Upgrades”</li> <li>■ Added “User Watchdog Internal Circuitry Timing Specification”</li> <li>■ Added “Initialization”</li> <li>■ Added “Raw Binary File Size”</li> </ul>
June 2012	2.4	<ul style="list-style-type: none"> <li>■ Added Figure 1, Figure 2, and Figure 3.</li> <li>■ Updated Table 1, Table 2, Table 3, Table 6, Table 11, Table 22, Table 23, Table 27, Table 29, Table 30, Table 31, Table 32, Table 35, Table 38, Table 39, Table 40, Table 41, Table 43, Table 56, and Table 59.</li> <li>■ Various edits throughout to fix bugs.</li> <li>■ Changed title of document to <i>Stratix V Device Datasheet</i>.</li> <li>■ Removed document from the Stratix V handbook and made it a separate document.</li> </ul>
February 2012	2.3	<ul style="list-style-type: none"> <li>■ Updated Table 1–22, Table 1–29, Table 1–31, and Table 1–31.</li> </ul>
December 2011	2.2	<ul style="list-style-type: none"> <li>■ Added Table 2–31.</li> <li>■ Updated Table 2–28 and Table 2–34.</li> </ul>
November 2011	2.1	<ul style="list-style-type: none"> <li>■ Added Table 2–2 and Table 2–21 and updated Table 2–5 with information about Stratix V GT devices.</li> <li>■ Updated Table 2–11, Table 2–13, Table 2–20, and Table 2–25.</li> <li>■ Various edits throughout to fix SPRs.</li> </ul>
May 2011	2.0	<ul style="list-style-type: none"> <li>■ Updated Table 2–4, Table 2–18, Table 2–19, Table 2–21, Table 2–22, Table 2–23, and Table 2–24.</li> <li>■ Updated the “DQ Logic Block and Memory Output Clock Jitter Specifications” title.</li> <li>■ Chapter moved to Volume 1.</li> <li>■ Minor text edits.</li> </ul>
December 2010	1.1	<ul style="list-style-type: none"> <li>■ Updated Table 1–2, Table 1–4, Table 1–19, and Table 1–23.</li> <li>■ Converted chapter to the new template.</li> <li>■ Minor text edits.</li> </ul>
July 2010	1.0	Initial release.